Machine Learning Based Feature Recognition and Image Processing in Sensing

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Message from the Guest Editor

Recently, we have seen a growing interest in the potential use of Feature Recognition and Image Processing. Feature Recognition (FR) is a technique to identify and extract application-specific information from input models for downstream engineering activities. Image feature recognition is an important area of artificial intelligence, aimed at recognizing targets and objects in various modes. Machine learning (ML) is a field of inquiry devoted to understanding and building methods that 'learn'. It is the method that leverages data to improve performance on some set of tasks and allows software applications to become more accurate at predicting outcomes without being explicitly programmed to do so. Benefiting from the excellent ability of feature learning, machine learning has achieved good results in the field of feature recognition. This Special Issue, therefore, aims to put together original research and review articles on recent advances, technologies, solutions, applications, and new challenges in the field of machine learning-based feature recognition.

Special Issue

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Message from the Editor-in-Chief

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